In the Specification:

Please amend the Specification such that the Abstract in its entirety reads as follows:

In <u>some aspects</u> a <u>first aspect</u>, a <u>first</u> method is provided for testing an integrated circuit (IC). The <u>first</u> method includes the steps of (1) selecting a bit from each of a plurality of memory arrays formed on an IC chip_t. (2) selecting one of the plurality of memory arrays_t and (3) storing the selected bit from the selected memory array. Numerous other aspects are provided.